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Index

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ARTICLES

All articles, including material that appears in the Computer Programs and Technical Aids Departments, are listed alphabetically by author and numbered sequentially. These sequential article numbers are used to identify the articles in the Key Words list, which begins on page 531.

1 Abraham, B. and MacKay, J., *Discussion* . . . . . October, 410–413
2 Anderson-Cook, C. M., *Understanding the Influence of Several Factors on a Cylindrical Response* . . . . . April, 167–180
3 Anderson, M. T.; Greenberg, B. S.; and Stokes, S. L., *Acceptance Sampling With Rectification When Inspection Errors Are Present* . . . . . October, 493–505
4 Arnold, J. C. and Reynolds, M. R., Jr., *CUSUM Control Charts With Variable Sample Sizes and Sampling Intervals* . . . . . January, 66–81
5 Bailey, S. P., *Discussion* . . . . . October, 426–431
6 Berdick, E. J., *An Efficient Scores Test for Comparing Several Measuring Devices* . . January, 96–103
7 Bingham, D. R. and Sitter, R. R., *Design Issues in Fractional Factorial Split-Plot Experiments* . . . . . January, 2–15
8 Breyfogle, F. W., III.; Enck, D.; and Meadows, B., *Discussion* . . . . . October, 424–425
9 Chakraborti, S.;van der Laan, P.; and Bakir, S. T., *Nonparametric Control Charts: An Overview and Some Results* . . . . . July, 304–315
10 Chang, T. C. and Gan, F. F., *Detecting Over Rejection in Testing of Integrated Circuits* . . . . . July, 356–364
11 Chen, G.; Cheng, S. W.; and Xie, H., *Monitoring Process Mean and Variability With One EWMA Chart* . . . . . April, 223–233
12 Chiah, C. and Hamada M., *Analyzing Experiments with Correlated Multiple Responses* . . . . . October, 451–465
13 Christensen, R., *Letter to the Editor* . . . . . April, 127–127
14 Crowder, S. V. and Eshleman, L., *Small Sample Properties of an Adaptive Filter Applied to Low Volume SPC* . . . . . January, 29–46
15 Del Castillo, E., *Some Properties of EWMA Feedback Quality Adjustment Schemes for Drifting Disturbances* . . . . . April, 153–166
16 Goos, P. Vandebroek, M., *Optimal Split-Plot Designs* . . . . . October, 436–450
17 Graves, S., *Tolerance Analysis Tailored to Your Organization* . . . . . July, 293–303
18 Hoerl, R. W., *Response* . . . . . October, 432–435
19 Hoerl, R. W., *Six Sigma Black Belts: What Do they Need to Know?* . . . . . October, 391–406
20 Hill, W. J., *Discussion* . . . . . October, 421–423
21 Lee, C. and Vardeman, S. B., *Interval Estimation of a Normal Process Mean from Rounded Data* . . . . . July, 335–348
22 Lee, M. K.; Hong, S. H.; Elsayed, E., *The Optimum Target Value Under Single and Two-Stage Screenings* . . . . . October, 506–514
23 Lewis, S. L.; Montgomery, D. C.; and Myers, R. H., *Confidence Interval Coverage for Designed Experiments Analyzed with GLMs* . . . . . July, 279–292
24 Lewis, S. L.; Montgomery, D. C.; and Myers, R. H., *Examples of Designed Experiments With Nonnormal Responses* . . . . . July, 265–278
25 Linna, K. W.; Woodall, W. H.; and Busby, K. L., *The Performance of Multivariate Control Charts in the Presence of Measurement Error* . . . . . July, 349–355

26 Linna, K. W. and Woodall, W. H., *Effect of Measurement Error on Shewhart Control Charts* . . . . . April, 213–222
27 Lu, C. and Reynolds, M. R., Jr., *CUSUM Charts for Monitoring an Autocorrelated Process* . . . . . July, 316–334
28 Mason, R. L.; Chou, Y.; and Young, J., *Applying Hotelling's T^2 Statistic to Batch Processes* . . . . . October, 466–479
29 McGrath, R. N. and Lin, D. K. J., *Confounding of Location and Dispersion Effects in Unreplicated Fractional Factorials* . . . . . April, 129–139
30 Montgomey, D. C.; Lawson, C.; Molnau, W. E.; and Elias, R., *Discussion* . . . October, 407–409
31 Nair, V. N.; Tank, B.; and Xu, L., *Bayesian Inference for Some Mixture Problems in Quality and Reliability* . . . . . January, 16–28
32 Nedumaran, G. and Pignatiello, J. J., Jr., *On Estimating $\bar{X}$ Control Chart Limits* . . . . . April, 206–212
33 Pignatiello, J. J., Jr. and Samuel, T. R., *Estimation of the Change Point of a Normal Process Mean in SPC Applications* . . . . . January, 82–95
34 Pulcini, G., *A Bounded Intensity Process for the Reliability of Repairable Equipment* . October, 480–492
35 Pyzdek, T., *Discussion* . . . . . October, 418–420
36 Reynolds, M. R., Jr. and Stoumbos, Z. G., *Monitoring the Process Mean and Variance Using Individual Observations and Variable Sampling Intervals* . . . . . April, 181–205
37 Snee, R. D., *Discussion* . . . . . October, 414–417
38 Shapiro, S. S. and Chen, L., *Composite Tests for the Gamma Distribution* . . . . . January, 47–59
39 Wludyka, P. S.; Nelson, P. R.; and Silva, P. R., *Power Curves for the Analysis of Means for Variances* . . . . . January, 60–65
40 Woodall, W. H., *Author's Reply* . . . . . April, 127–128
41 Wright, C. M.; Booth, D. E.; and Hu, M. Y., *Joint Estimation: SPC Method for Short-Run Autocorrelated Data* . . . . . July, 365–378
42 Wu, Z.; Yeo, S. H.; and Spedding, T. A., *A Synthetic Control Chart for Detecting Fraction Noncomforming Increases* . . . . . January, 104–111
43 Ye, K. Q.; Hamada, M.; and Wu, C. F. J., *A Step-Down Method for Analyzing Unreplicated Factorial Designs* . . . . . April, 140–152

DEPARTMENTS

Computer Programs

44 Molnau, W. E.; Runger, G. C.; Montgomery, D. C.; Skinner, K. R.; Loredo, E. N.; and Prabhu, S. S., *A Program for ARL Calculation for Multivariate EWMA Charts* . . . . . October, 515–521
45 Wu, Z. and Yeo, S. H., *Implementing Synthetic Control Charts for Attributes* . . . . . January, 112–114
46 McWilliams, T. P.; Saniga, E. M.; and Davis, D. J., *Economic-Statistical Design of $\bar{X}$ and R or $\bar{X}$ and S Charts* . . . . . April, 234–241
47 Turner, C. D.,Jr.;Batson, R. G.; Sullivan, J. H.; and Woodall, W. H., *A Program for Retrospective Change-Point Analysis of Individual Observations* . . . . . April, 242-257

Technical Aids

48 Nelson, L. S., *How to Form and Inform a Quality Improvement Team* . . . . . October, 522–523
49 Nelson, L. S., *Is Your Mind a Suitable Source of Random Digits?* . . . . . July, 379–381
50 Nelson, L. S., *Test on Quality Control Statistics and Concepts* . . . . . January, 115–117
51 Nelson, L. S., *The Marvelous Inspection Machine* . . . . . April, 258–258

Book Reviews

Box on Quality and Discovery with Design, Control, and Robustness by G. Tiao, S. Bisgaard, W. Hill, D. Pena, and S. Stigler, eds. . . . . C. BORROR July, 386–387
Design and Analysis of Experiments, 5th ed. by D. C. Montgomery . K. A. F. COPELAND July, 382–383
DOE Simplified: Practical Tools for Effective Experimentation by M. J. Anderson and P. J. Whitcomb . . . . . K. A. F. COPELAND January, 118–118
Introduction to Statistical Quality Control, Fourth Edition by D. C. Montgomery . . . . . C. CHAMP October, 524–525
Managing Six Sigma: A Practical Guide to Understanding, Assessing, and Implementing the Strategy that Yields Bottom Line Success by F. W. Breyfogle, III., J. M. Cupello, and B. Meadows . . . . . L. DANIELS October, 525–526
Miller and Freund's Probability and Statistics for Engineers, 6th ed. by R. A. Johnson . . . . . C. BORROR January, 122–122
Minitab Handbook, 4th ed. by B. Ryan and B. Joiner . . . . . C. BORROR January, 122–123
Nonparametric Statistical Methods, 2nd ed. by M. Hollander and D. A. Wolfe .C. BORROR April, 259–259
Practical Nonparametric Statistics, 3rd ed. by W. J. Conover . . . . . C. BORROR April, 260–260
Practical Strategies for Experimenting by G. K. Robinson . . . . . C. BORROR October, 526–527
Quality Engineering Handbook by T. Pyzdek . . . . . L. DANIELS January, 118–119
Robust Diagnostic Regression Analysis by A. C. Atkinson and M. Riani J. W. WISNOWSKI July, 383–384
SPC: Practical Understanding of Capability by Implementing Statistical Quality Control, 3rd ed. by J. C. Abbott . . . . . L. S. NELSON April, 260–262
Statistics: A First Course, 7th ed. by J. E. Freund and B. M. Perles . . . . . C. BORROR April, 262–263
Statistics and Data Analysis: from Elementary to Intermediate by A. C. Tamhane and D. D. Dunlop . . . . . M. M. KILGO, III July, 385–386
Statistical Methods for the Reliability of Repairable Systems by S. E. Rigdon and A. P. Basu . . . . . C. LAWSON October, 527–528
Statistical Process Analysis by L. C. Alwan . . . . . L. ZIMMER July, 384–385
Statistical Quality Control: A Loss Minimization Approach by D. Trietsch . . . . . C. P. QUESENBERRY January, 119–122

Book Reviewers

Borror, C. M. . . . . January, 122–122
Borror, C. M. . . . . January, 122–123
Borror, C. M. . . . . April, 259–259
Borror, C. M. . . . . April, 260–260
Borror, C. M. . . . . April, 262–263
Borror, C. M. . . . . July, 386–387
Borror, C. M. . . . . October, 526–527
Champ, C. . . . . October, 524–525
Copeland, K. A. F. . . . . January, 118–118
Copeland, K. A. F. . . . . July, 382–383
Daniels, L. . . . . January, 118–119
Daniels, L. . . . . October, 525–526
Kilgo, M. M., III . . . . . July, 385–386
Lawson, C. . . . . October, 527–528
Nelson, L. S. . . . . April, 260–262
Quesenberry, C. . . . . January, 119–122
Wisnowski, J. W. . . . . July, 383–384
Zimmer, L. . . . . July, 384–385

MISCELLANEOUS

Editorial Collaborators . . . . . October, 533

KEY WORDS

The numbers listed by the key words are the identification numbers assigned to the articles as listed on the previous pages.

Acceptance Sampling; 35
Adaptive Filtering; 14
Analysis of Variance; 6
Anderson Darling Test; 38
Autocorrelated Observations; 14, 27, 41
Autoregressive Moving Average Model; 27

Average Number of Observations to Signal; 36
Average Run Length; 11, 27, 32, 44
Average Time to Signal; 36, 42, 45
Bayesian Methods; 31
Bernoulli Distribution; 10
Binomial Distribution; 10
Bi-randomization Designs; 16
Black Belt; 19
Case Study; 48
Certified Quality Engineer; 19
Change Point; 9, 47
Change Point Estimation; 33
Circular-linear Data; 2
Confounding; 29
Control Charts; 11, 26, 32, 44
Control Limits; 32
Correlated Data; 22
Coverage Probability; 21
Cumulative Sum Control Charts; 4, 9, 10, 27, 33
Design of Experiments; 16, 23, 24
Directional Data; 2
Dispersion; 29
Distribution-Free Procedures; 9
D-optimality; 16
Economic Control Charts; 46
Economic Design; 46
Expected Values; 49
Experimentwise Error; 43
Exponential Weighted Moving Average; 15
Exponentially Weighted Moving Average Control Charts; 9, 27, 33, 36
Factorial Designs; 2, 12
Feedback Control; 15
First Order Moving Average Model; 27
Fractional Factorial Designs; 12, 29
Gaging; 21
Gamma Distribution; 38
Generalized Linear Models; 23, 24
Greenwood Statistic; 38
Grubb's Model; 6
Homogeneity of Variances; 39
Hypothesis Testing; 6, 49
Individual Error Rate; 43
Likelihood; 21, 31
Manufacturing; 31
Manufacturing Cost; 17
Master Black Belt; 19
Maximum Likelihood; 47
Measurement Error; 26
Minimum Aberration; 7
Monte Carlo Simulations; 32
Moving Range Control Charts; 36, 47
Multivariate Normal Distribution; 12
Multivariate Quality Control; 25, 28
Multivariate t Distribution; 32
Nonconstant Variance; 23, 24
Nonnormality; 23
Nonnormal Response; 24
Non-sampling Error; 3
np Control Charts; 42, 45
Optimum Target Value; 22
Outliers; 28
Pareto; 17
Phase I; 28
Phase II; 28
Poisson Process; 34
Posterior Distributions; 31
Power; 39, 43
Precision; 7
Probability Integral Transformation; 38
Process Adjustment; 15
Process Control; 46
Process Drift; 15
Process Improvement; 33
Quality Control; 31, 33, 51
Random Digits; 49
Reliability; 31, 34
Repairable Systems; 34
Resolution; 7
Robust Parameter Design; 12
Run Length Distributions; 32
Sample Size; 39
Scale Parameter; 29
Screening; 22
Selection Bias; 3
Shewhart Control Charts; 9, 27, 36
Shewhart $\bar{X}$ Control Chart; 33
Special Cause Identification; 33
Specifications; 51
Split-Plot Designs; 16
Statistical Process Control; 10, 25, 27, 32, 33, 36, 41, 44
Steady State; 36
Tolerance Limits; 17
Variance Components; 6
Variable Sample Sizes; 4
Variable Sampling; 4
Variable Sampling Interval Control Charts; 36
Variables Control Charts; 46
Variables Data; 11
X Control Charts; 36, 47